

Search Notes

Application/Control No.

10/632,082

Examiner

Jason M. Han

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2875

SEARCHED

Class	Subclass	Date	Examiner
362	260	5/2/2006	JMH
362	217-225	5/2/2006	JMH
362	646	5/2/2006	JMH
439	56	5/2/2006	JMH
439	235	5/2/2006	JMH
349	58	5/2/2006	JMH
349	70-71	5/2/2006	JMH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	5/2/2006	JMH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner